WAVELINK WL-250

200mm Semi-Automatic Probe Station

The **WaveLink 250** represents the upper limit in computer-controlled analytical wafer probing. Designed to be the flagship of our RF/MW line, it is equally at home at 5 fA as it is at 110 GHz. Whether you simply need EMI or RFI isolation, or frost-free characterization at -65 °C, the WL-250 should be your platform of choice. SIGNATONE, you asked - *We Listened!*

PERFORMANCE, QUALITY, VALUE

SIGNATONE®

Advanced Microprobing Solutions Since 1968

WAVELINK WL-250

Specifications

- 200mm XY stage travel
- Independent cal and wafer chuck
- 50mm platen range, with lock
- 50mm programmable microscope transport
- Pneumatic 4" microscope lift
- Chuck X-Y Resolution: .1µ
- Chuck X-Y Repeatability: 1µ
- Chuck X-Y Accuracy: ±3µ
- Chuck Z Resolution: .1µ
- Chuck Z Accuracy: .25µ
- Chuck Θ: ±6 degrees

X-Y Motion Control

- "Point & Shoot" movements
- 8 directional arrows with variable speed control
- Wafer map "Pick & Move"
- "Go To" commands

Z Motion Control

- Separate contact/overdrive height
- Z motion speed control
- Safety lock
- Soft Z with edge sense circuit (for use w/probe card edge sense)

Programming

- Wafer Map design editor
- Selective programming
- Learn position
- Subroutine with chuck or Computer aided Probe

Interfacing

- DDE interface integrated with ICS Metrics for instrument control of most Keithley and Agilent instruments
- Application SW for Keithley 2400 Series
- DDE compatible with HP VEE
- DDE compatible with NI LABView
- GPIB compatible with NI LABView

User-Friendly Features

- Stores setup and programs for easy retrieval
- Icons for most applications
- Basic Run mode guides the user through basic operations
- On-Screen video display option
- Wafer map position indicator

Other Features

- Microscope X-Y-Z and Zoom control
- Color wafer bin mapping with 16 colors
- Hot chuck interface and control
- Accepts probe cards
- Available vibration isolation tables
- Optional Controller/Instrumentation rack

Integrated Probing Solutions For Testing

- S-Parameters, 1/f
- Load-Pull, Noise Figure
- V_{TH}
- T_{OX}
- CV/IV
- Sub-Threshold Leakage to 5 fA
- Resistivity
- WLR
- Dark Current
- Pulse mode 10A/100V Measurements

ICS-Metrics Software

ICS-Metrics integrates Agilent and Keithley DC/CV instrumentation for the automated characterization of semiconductor parameters

- Graphical user interface for all instrument functions
- Simple, pre-configured test formats for semiconductor devices
- Data collection and storage
- Sequential test execution
- Data analysis and reporting

SIGNATONE

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